Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10540658	MATHIES ET AL.
Examiner	Art Unit

1637

SEARCHED			
Class	Subclass	Date	Examiner

Young J Kim

SEARCH NOTES		
Search Notes	Date	Examiner
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	2/8/2008	/YJK/
see enclosed for text-search strategies	2/8/2008	/YJK/
Updated - see enclosed for text-search strategies	10/2/2008	/YJK/
Updated- see enclosed for text-search strategy	2/26/2009	/YJK/

INTERFERENCE SEARCH			
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